

**Search Notes**

Application/Control No.

10/812,419

Examiner

James Cho

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2819

**SEARCHED**

Class	Subclass	Date	Examiner
326	104-106, 112,136	7/8/2005	JC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
searched above		7/8/2005	JC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS search, IEEE Xplore search	7/8/2005	JC